

Adolf Canillas

List of Publications by Year in descending order

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64
papers

1,517
citations

304743

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37
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64
all docs

64
docs citations

64
times ranked

1167
citing authors

#	ARTICLE	IF	CITATIONS
1	Analytic inversion of the Mueller-Jones polarization matrices for homogeneous media. Optics Letters, 2010, 35, 559.	3.3	104
2	Mueller matrix microscope with a dual continuous rotating compensator setup and digital demodulation. Applied Optics, 2014, 53, 2236.	1.8	104
3	Effective dielectric function of mixtures of three or more materials: a numerical procedure for computations. Surface Science, 2000, 453, 9-17.	1.9	79
4	Relation between 2D/3D chirality and the appearance of chiroptical effects in real nanostructures. Optics Express, 2016, 24, 2242.	3.4	70
5	Insitu spectroellipsometric study of the nucleation and growth of amorphous silicon. Journal of Applied Physics, 1990, 68, 2752-2759.	2.5	68
6	Emergence of Supramolecular Chirality by Flows. ChemPhysChem, 2010, 11, 3511-3516.	2.1	66
7	Chiral sign selection on the aggregates of diprotonated tetrakis(4-sulfonatophenyl)porphyrin by traces of unidentified chiral contaminants present in the ultra-pure water used as solvent. Chirality, 2009, 21, 408-412.	2.6	62
8	Phase-modulated ellipsometer using a Fourier transform infrared spectrometer for real time applications. Review of Scientific Instruments, 1993, 64, 2153-2159.	1.3	57
9	On the Mechano-Chiral Effect of Vortical Flows on the Dichroic Spectra of 5-Phenyl-10,15,20-tris(4-sulfonatophenyl)porphyrin Aggregates. Chemistry - A European Journal, 2008, 14, 6438-6443.	1.3	56
10	Pseudopolar decomposition of the Jones and Mueller-Jones exponential polarization matrices. Journal of the Optical Society of America A: Optics and Image Science, and Vision, 2009, 26, 783.	1.5	53
11	Influence of pressure and radio frequency power on deposition rate and structural properties of hydrogenated amorphous silicon thin films prepared by plasma deposition. Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films, 1991, 9, 2216-2221.	2.1	52
12	Evidence of induced chirality in stirred solutions of supramolecular nanofibers. Optics Letters, 2009, 34, 2177.	3.3	50
13	Determination of the components of the gyration tensor of quartz by oblique incidence transmission two-modulator generalized ellipsometry. Applied Optics, 2009, 48, 5307.	2.1	44
14	Ellipsometric study of a-Si:H thin films deposited by square wave modulated rf glow discharge. Journal of Applied Physics, 1991, 69, 632-638.	2.5	39
15	Kinetic Control of the Supramolecular Chirality of Porphyrin Aggregates. Chemistry - A European Journal, 2012, 18, 8820-8826.	3.3	35
16	Real time controlled rf reactor for deposition of a-Si:H thin films. Vacuum, 1989, 39, 795-798.	3.5	34
17	Reversible Mechanical Induction of Optical Activity in Solutions of Soft Matter Nanophases. Chemistry - an Asian Journal, 2009, 4, 1687-1696.	3.3	34
18	Effects of plasma processing on the microstructural properties of silicon powders. Plasma Sources Science and Technology, 1994, 3, 348-354.	3.1	33

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19	In situ optical characterizations for rf plasma deposited a-Si: H thin films. <i>Vacuum</i> , 1989, 39, 785-787.	3.5	30
20	Hydrodynamic Effects in Soft Matter Self-Assembly: The Case of J-Aggregates of Amphiphilic Porphyrins. <i>Chemical Record</i> , 2017, 17, 713-724.	5.8	28
21	Spectroscopic ellipsometric study of tetrahedral amorphous carbon films: optical properties and modelling. <i>Diamond and Related Materials</i> , 2001, 10, 1132-1136.	3.9	27
22	Flow Effects in Supramolecular Chirality. <i>Israel Journal of Chemistry</i> , 2011, 51, 1007-1016.	2.3	23
23	Chirality generated by flows in pseudocyanine dye J-aggregates: Revisiting 40 years old reports. <i>Chirality</i> , 2011, 23, 585-592.	2.6	22
24	An IR phase-modulated ellipsometer using a Fourier transform spectrometer for in situ applications. <i>Thin Solid Films</i> , 1993, 234, 318-322.	1.8	18
25	Spontaneous mirror-symmetry breaking coupled to top-bottom chirality transfer: from porphyrin self-assembly to scalemic Diels-Alder adducts. <i>Chemical Communications</i> , 2019, 55, 12219-12222.	4.1	18
26	Structure vs. excitonic transitions in self-assembled porphyrin nanotubes and their effect on light absorption and scattering. <i>Nanoscale</i> , 2015, 7, 20435-20441.	5.6	17
27	Properties of amorphous silicon thin films grown in square wave modulated silane rf discharges. <i>Journal of Applied Physics</i> , 1992, 71, 1546-1548.	2.5	15
28	Reversible and irreversible emergence of chiroptical signals in J-aggregates of achiral 4-sulfonatophenyl substituted porphyrins: intrinsic chirality vs. chiral ordering in the solution. <i>Chemical Communications</i> , 2016, 52, 10874-10877.	4.1	15
29	Analytic inversion of the Mueller-Jones polarization matrices for homogeneous media: erratum. <i>Optics Letters</i> , 2010, 35, 3525.	3.3	14
30	Transmission Mueller matrix ellipsometry of chirality switching phenomena. <i>Thin Solid Films</i> , 2011, 519, 2617-2623.	1.8	14
31	Transmission ellipsometry of anisotropic substrates and thin films at oblique incidence. Handling multiple reflections. <i>Thin Solid Films</i> , 2014, 571, 701-705.	1.8	14
32	Optical security verification by synthesizing thin films with unique polarimetric signatures. <i>Optics Letters</i> , 2015, 40, 5399.	3.3	14
33	Effect of substrate temperature on deposition rate of rf plasma-deposited hydrogenated amorphous silicon thin films. <i>Journal of Applied Physics</i> , 1991, 69, 3757-3759.	2.5	13
34	Alignment and Chirality of Porphyrin J Aggregates Formed at the Liquid-Liquid Interface of a Centrifugal Liquid Membrane Cell. <i>Langmuir</i> , 2013, 29, 7249-7256.	3.5	13
35	Chiral Biases in Solids by Effect of Shear Gradients: A Speculation on the Deterministic Origin of Biological Homochirality. <i>Origins of Life and Evolution of Biospheres</i> , 2010, 40, 27-40.	1.9	12
36	Error minimization method for spectroscopic and phase-modulated ellipsometric measurements on highly transparent thin films. <i>Journal of the Optical Society of America A: Optics and Image Science, and Vision</i> , 1993, 10, 713.	1.5	11

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37	Numerical algorithm for spectroscopic ellipsometry of thick transparent films. <i>Applied Optics</i> , 1998, 37, 1177.	2.1	11
38	Plasma-deposited silicon nitride films with low hydrogen content for amorphous silicon thin-film transistors application. <i>Sensors and Actuators A: Physical</i> , 1993, 37-38, 333-336.	4.1	10
39	Optimized calibration method for Fourier transform infrared phase-modulated ellipsometry. <i>Thin Solid Films</i> , 1999, 354, 187-194.	1.8	10
40	Achiral to Chiral Transition in Benzil Solidification: Analogies with Racemic Conglomerates Systems Showing Deracemization. <i>Chirality</i> , 2013, 25, 393-399.	2.6	10
41	Optical, vibrational and compositional study of amorphous silicon oxynitride thin films grown by an RF plasma using N ₂ + SiH ₄ gas mixtures. <i>Applied Surface Science</i> , 1993, 70-71, 695-700.	6.1	9
42	Measurement of the optical activity of anisotropic samples by transmission Mueller matrix ellipsometry. <i>EPJ Web of Conferences</i> , 2010, 5, 03001.	0.3	9
43	Mueller matrix polarimetry on a Young's double-slit experiment analog. <i>Optics Letters</i> , 2017, 42, 3900.	3.3	9
44	Effect of hydrogen dilution on the growth of hydrogenated amorphous silicon studied by in-situ phase-modulated ellipsometry. <i>Thin Solid Films</i> , 1993, 228, 109-112.	1.8	8
45	Application of transmission ellipsometry to the determination of CD spectra of porphyrin aggregates solid-state samples. <i>Physica Status Solidi (A) Applications and Materials Science</i> , 2008, 205, 797-801.	1.8	8
46	Optical characterization of colloidal crystals based on dissymmetric metal-coated oxide submicrospheres. <i>Thin Solid Films</i> , 2008, 517, 1053-1057.	1.8	8
47	Mueller matrix microscopy on a Morpho butterfly. <i>Journal of Physics: Conference Series</i> , 2015, 605, 012008.	0.4	8
48	Optical and electrical properties of a-Si _x Ny:H films prepared by rf plasma using N ₂ +SiH ₄ gas mixtures. <i>Journal of Non-Crystalline Solids</i> , 1991, 137-138, 895-898.	3.1	7
49	Effects of deposition temperature on properties of r.f. glow discharge amorphous silicon thin films. <i>Thin Solid Films</i> , 1991, 205, 140-145.	1.8	7
50	Visible and infrared ellipsometry applied to the study of metal-containing diamond-like carbon coatings. <i>Thin Solid Films</i> , 2004, 455-456, 370-375.	1.8	7
51	Calibration improvement of Fourier transform infrared phase-modulated ellipsometry. <i>Journal of the Optical Society of America A: Optics and Image Science, and Vision</i> , 1996, 13, 2461.	1.5	5
52	Application of FTIR phase-modulated ellipsometry to the characterisation of thin films on surface-enhanced IR absorption active substrates. <i>Thin Solid Films</i> , 2001, 398-399, 99-103.	1.8	5
53	Quaternion algebra for Stokes' Mueller formalism. <i>Journal of the Optical Society of America A: Optics and Image Science, and Vision</i> , 2019, 36, 492.	1.5	5
54	Heterogeneous distribution of B-site cations in BaZrxTi1-xO ₃ epitaxial thin films grown on (001) SrTiO ₃ by pulsed laser deposition. <i>Applied Surface Science</i> , 2016, 381, 12-16.	6.1	4

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55	Surface roughness evolution in the growth of a-Si: H thin films studied by ellipsometry. Surface Science, 1991, 251-252, 191-194.	1.9	3
56	In situ real-time ellipsometric study of the growth of r.f. plasma deposited amorphous hydrogenated silicon oxynitride thin films. Thin Solid Films, 1993, 228, 137-140.	1.8	3
57	FTIR phase-modulated ellipsometry characterization of hydrogenated amorphous silicon nitride thin films with embedded nanoparticles. Thin Solid Films, 2004, 455-456, 167-171.	1.8	3
58	Optical characterization of ns-SiN:H in the infrared by spectroscopic ellipsometry. Applied Surface Science, 2006, 253, 65-69.	6.1	3
59	Effects of r.f. power on optical and electrical properties of plasma-deposited hydrogenated amorphous silicon thin films. Sensors and Actuators A: Physical, 1993, 37-38, 733-736.	4.1	2
60	Detection and characterization of single nanoparticles by interferometric phase modulated ellipsometry. Thin Solid Films, 2011, 519, 2801-2805.	1.8	2
61	Study of thin films of transparent electronic materials by phase-modulated spectroellipsometry. Thin Solid Films, 1993, 233, 223-226.	1.8	1
62	Retrieval of the non-depolarizing components of depolarizing Mueller matrices by using symmetry conditions and least squares minimization. Applied Surface Science, 2017, 421, 697-701.	6.1	1
63	Study of the oxidization of ns-SiNx:H thin films using FTIR phase modulated ellipsometry. , 2004, , .		1
64	Deposition of amorphous silicon films from an electrostatically confined silane plasma. Vacuum, 1987, 37, 443-444.	3.5	0